

PTO-1449  <b>Information Disclosure Citation in an Application</b>	Application No.	Applicant(s)	
	Unassigned	Pascal Huyghe et al.	
	Docket Number 064441.0263	Group Art Unit Unknown	Filing Date June 27, 2003

## U.S. PATENT DOCUMENTS

	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
A.						
B.						
C.						
D.						
E.						
F.						
G.						
H.						
I.						
J.						
K.						

## FOREIGN PATENT DOCUMENTS

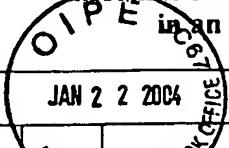
	DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES
L.						
M.						
N.						
O.						
P.						
Q.						

## NON-PATENT DOCUMENTS

	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)			DATE
MA R.	Edward Suttle et al.'s "Streamlining the front-end reticle fabrication process by improving mask ordering" at internet address <http://www.micromagazine.com/archive/02/06/suttle.html> and published in June 2002 Issue of Micro Magazine. 10 Pages			June 2002
MA S.	Brock Hotaling, "MaskPilot Revolutionizes Semiconductor Software," <u>Reticle and Mask Solutions</u> , Vol. I, No. 1, Fall 2002, 4 Pages			Fall 2002
T.	Photronics, Inc., "Photronics eBeam Phase Masks: Tackling the Challenges of Special Lightwave Applications." <u>Reticle and Mask Solutions</u> , Vol. XIII, No. 1, Spring 2002, 4 Pages			Spring 2002

EXAMINER  <i>Heughe</i>	DATE CONSIDERED  <i>21/24/2006</i>
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

<b>Information Disclosure Citation in an Application</b>  <b>JAN 22 2004</b>			Application No.	Applicant(s)		
			10/607,944	Pascal Huyghe et al.		
			Docket Number 064441.0263	Group Art Unit 2122	Filing Date June 27, 2003	
<b>U.S. PATENT DOCUMENTS</b>						
DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
A. 5909570	6/1/99	Webber	395	500	6/9/97	
B. 6012070	1/4/00	Cheng et al.	707	505	11/15/96	
C. 2002/0184266	12/5/02	Blessin	707	513	3/20/02	
D.						
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<b>FOREIGN PATENT DOCUMENTS</b>						
DOCUMENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
L. 01/63446 A2 ✓	8/30/01	WO	G06F	17/00	X	
M. 02/03141 A2 ✓	1/10/02	WO	G03F	1/00	X	
N.						
O.						
P.						
Q.						
<b>NON-PATENT DOCUMENTS</b>						
DOCUMENT (Including Author, Title, Source, and Pertinent Pages)						DATE
R. PCT International Search Report application number PCT/US03/20345, 7 pages.						Mailing 12/19/03
S.						
T.						
EXAMINER <i>Haynes</i>				DATE CONSIDERED <i>2/24/2006</i>		
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